



Patent Application Serial No. Not Yet Assigned

VERSION WITH MARKINGS TO SHOW CHANGES MADE

The claims have been amended as follows:

8. (Amended) A scanning transmission electron microscope, equipped with the element mapping unit according to Claim 1 [or Claim 8], that irradiates electron beams onto an object to be analyzed and supplies the electron beams, which have transmitted through the object to be analyzed, to the element mapping unit.